

Fig.1

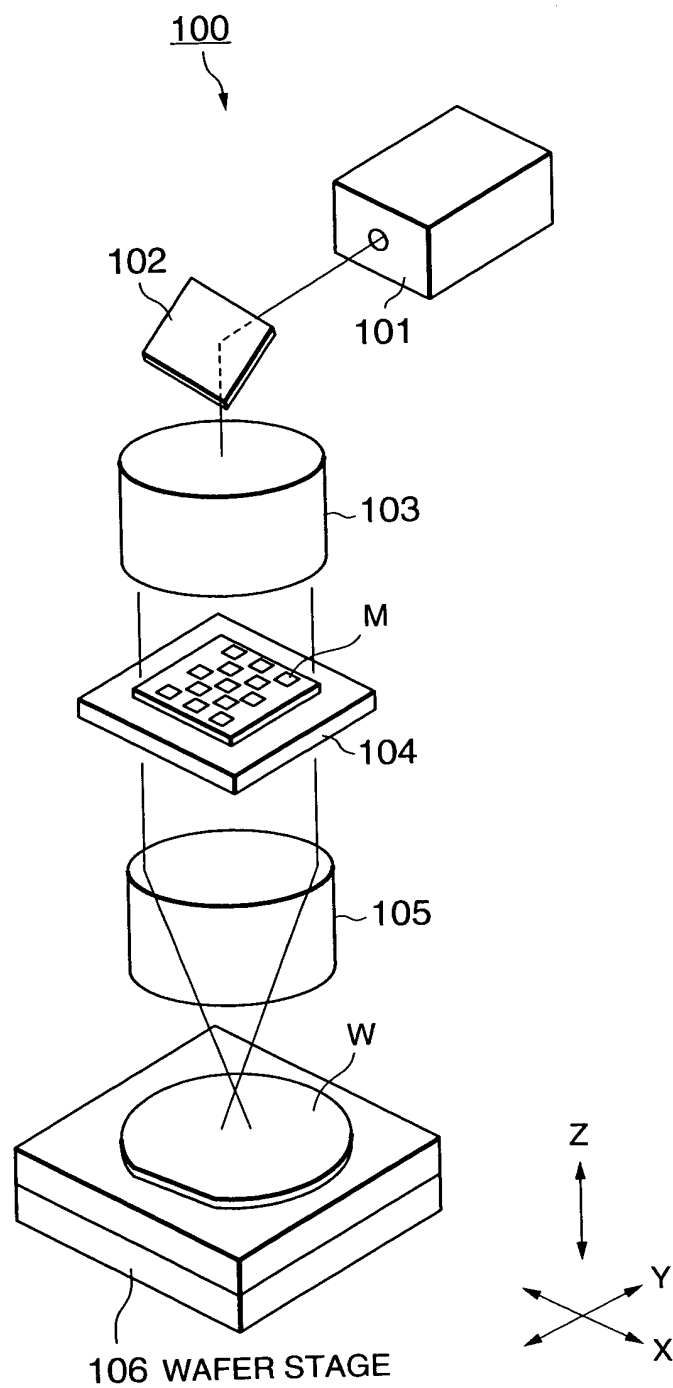


Fig.2

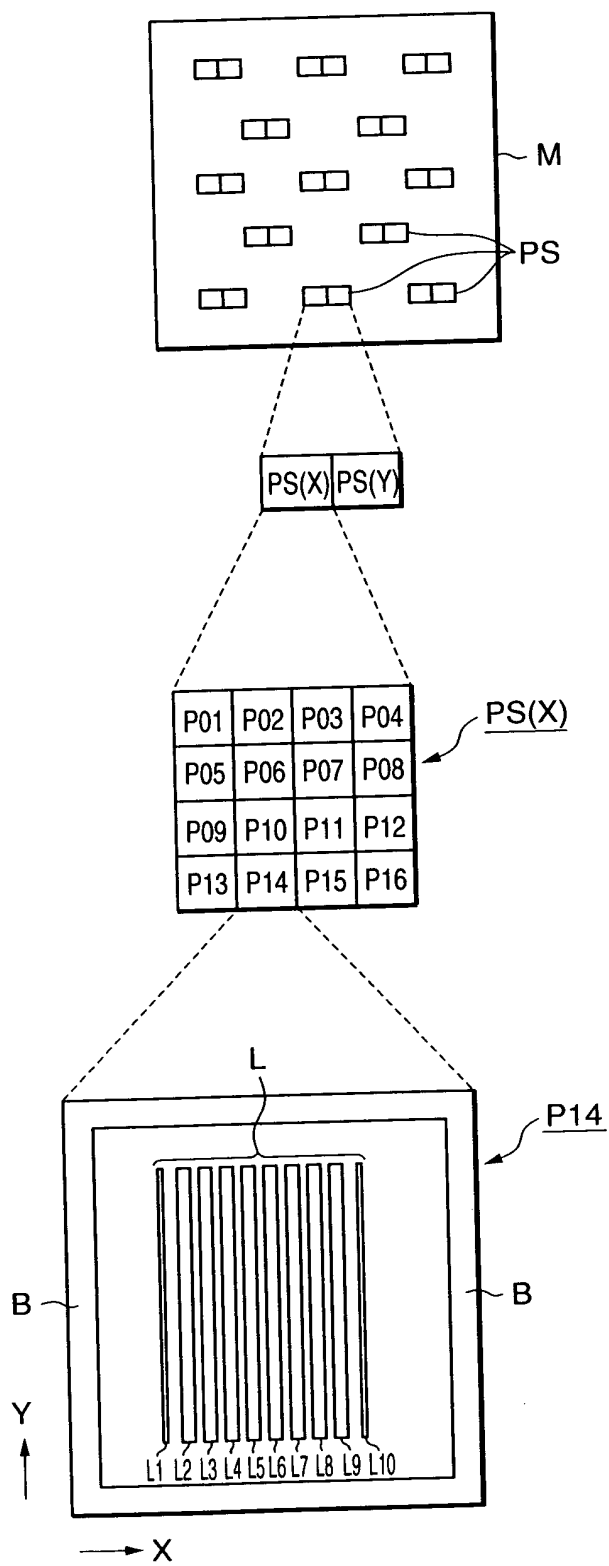


Fig.3(a)

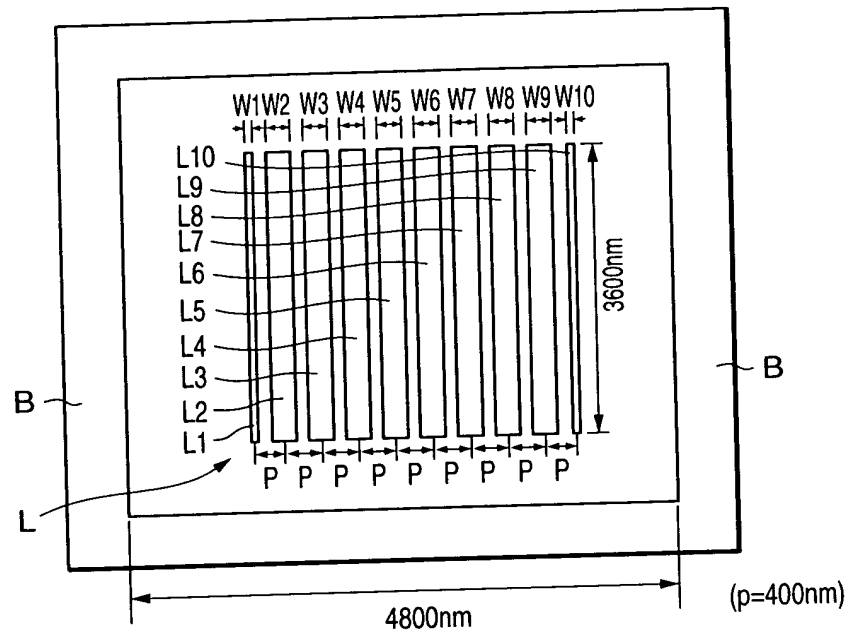


Fig.3(b)

		P02	P03	P04	
	W1, W10 =200nm	// // =195nm	// // =190nm	// // =185nm	
P01					
P06	// // =180nm	// // =175nm	// // =170nm	// // =165nm	P07
P05					P08
P10	// // =160nm	// // =155nm	// // =150nm	// // =145nm	P11
P09					P12
P13	// // =140nm	// // =135nm	// // =130nm	// // =125nm	P16
		P14	P15		

Fig.4

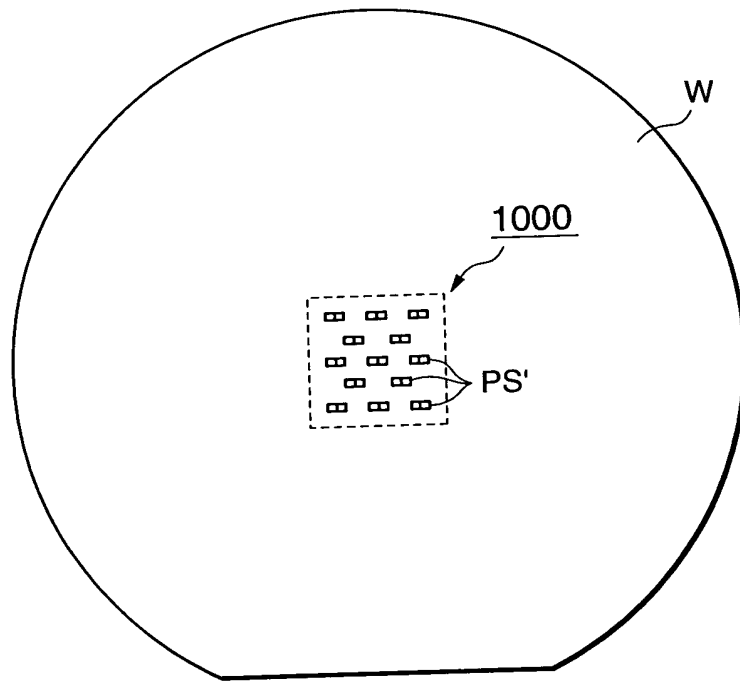


Fig.5(a)

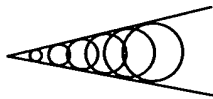


Fig.5(b)

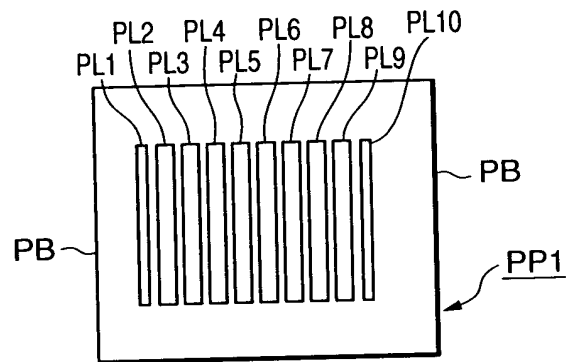


Fig.5(c)

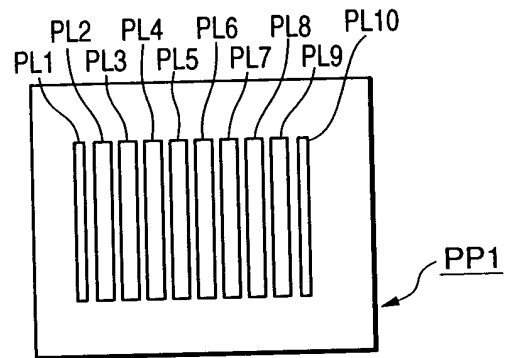


Fig.5(d)

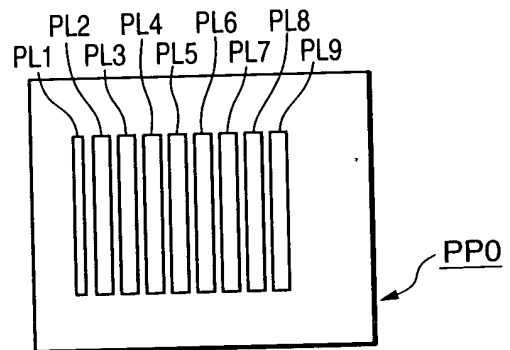


Fig.5(e)

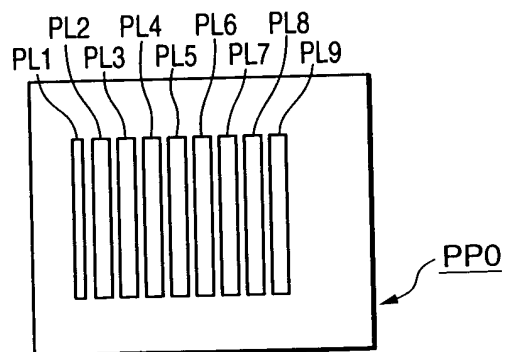


Fig. 6(b)

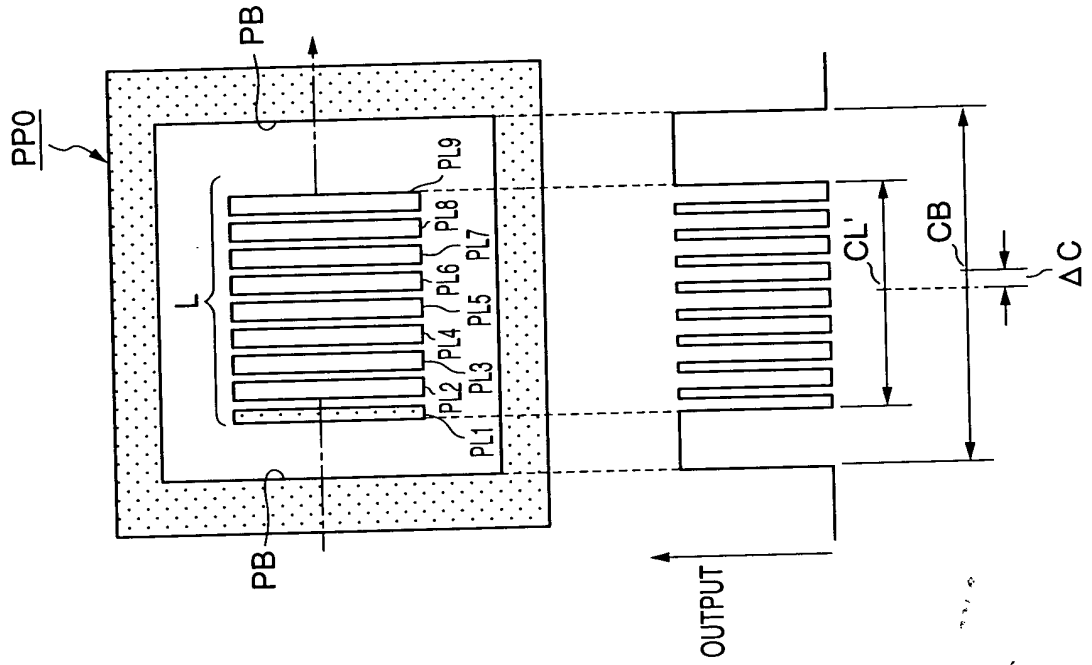


Fig. 6(a)

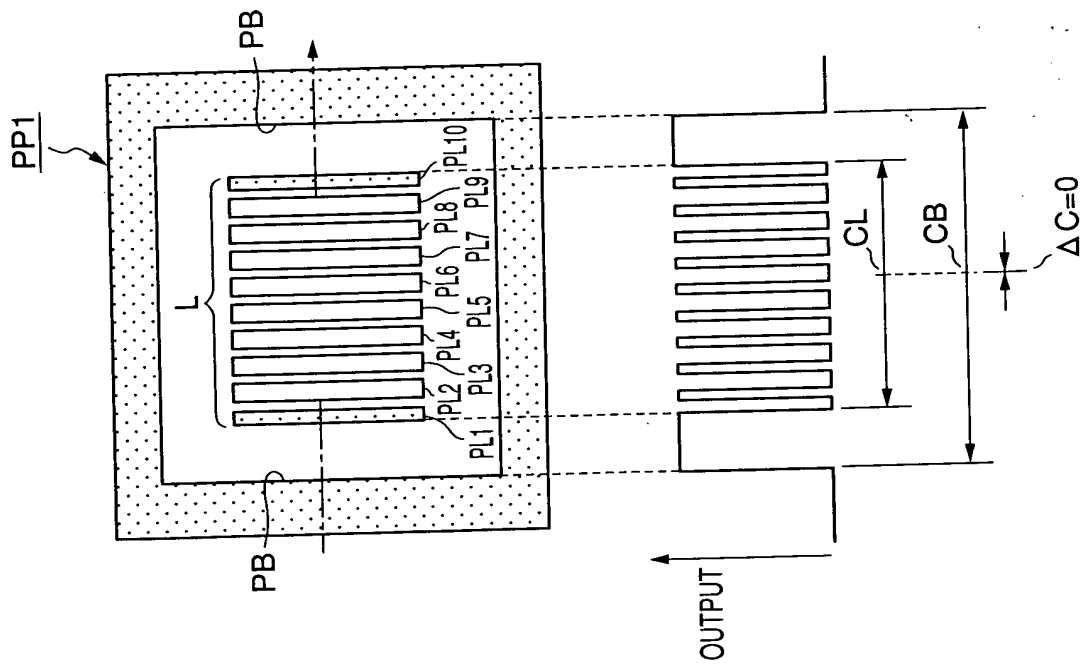


Fig.7

RELATIVE POSITIONAL DEVIATION
(RESULT OF OVERLAY MEASUREMENT)

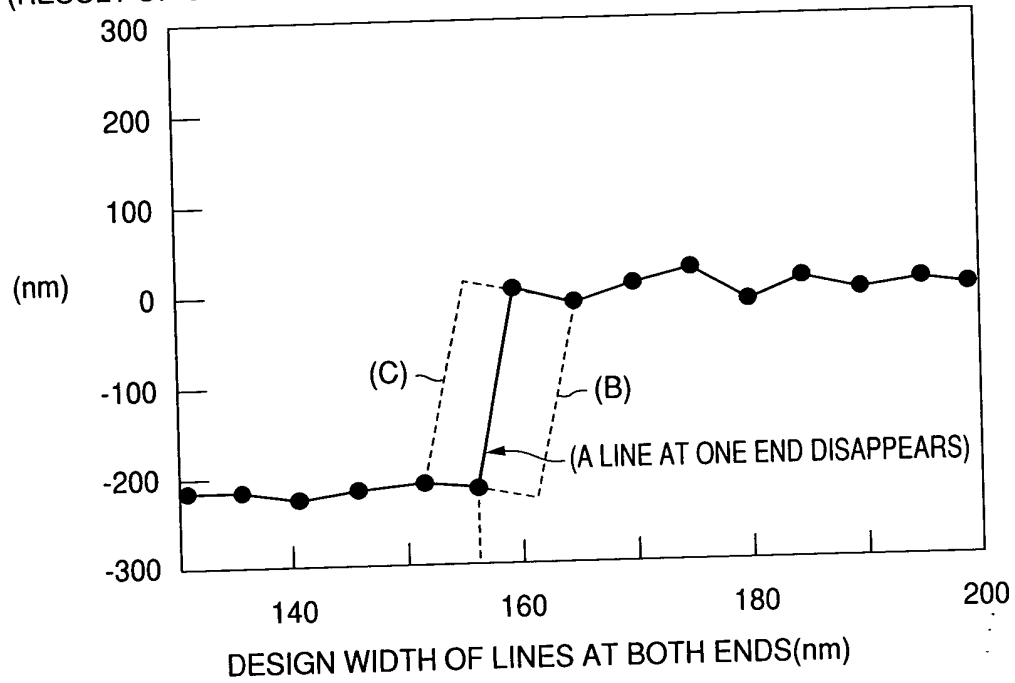


Fig.8

LINE WIDTH RELATED TO A MISSING
LINE PATTERN AT ONE END

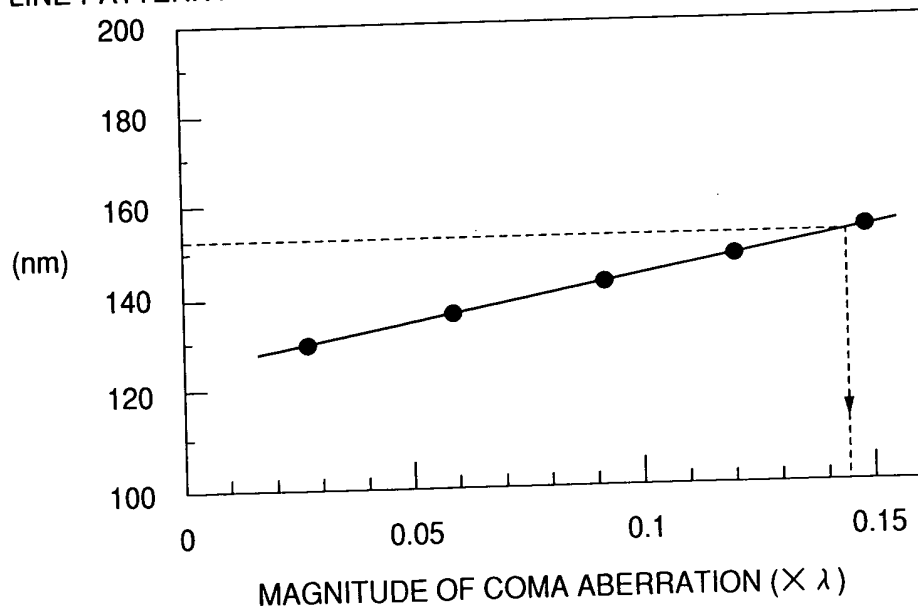


Fig.9

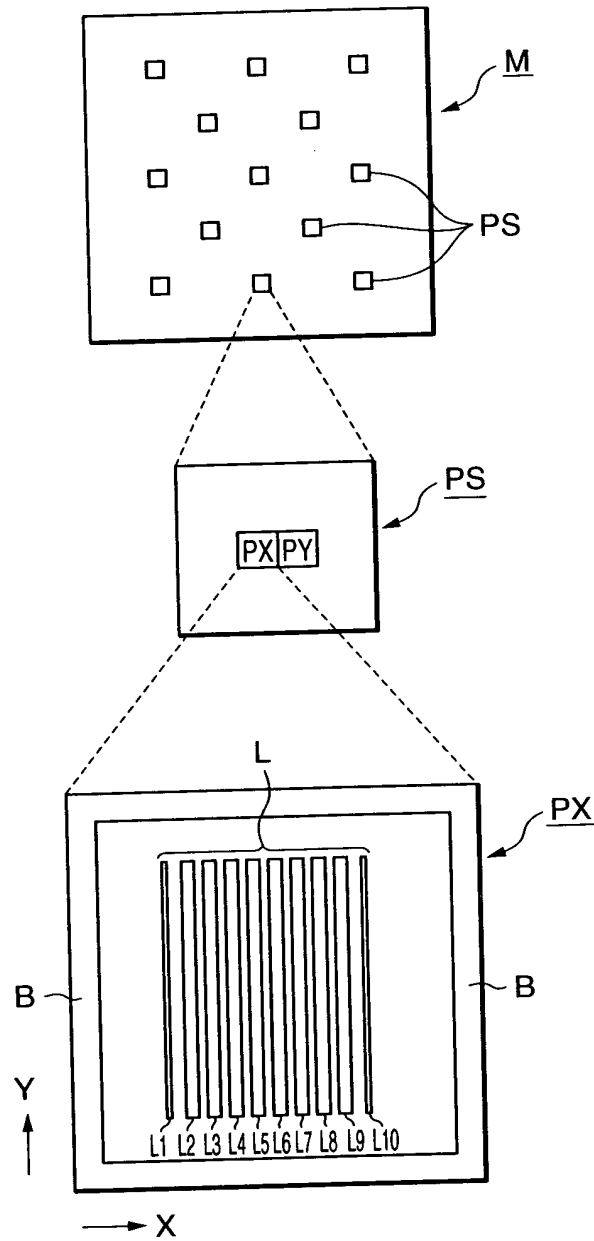


Fig.10(a)

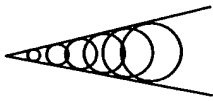


Fig.10(b)

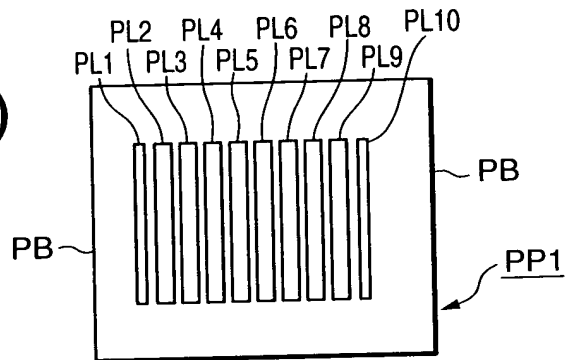


Fig.10(c)

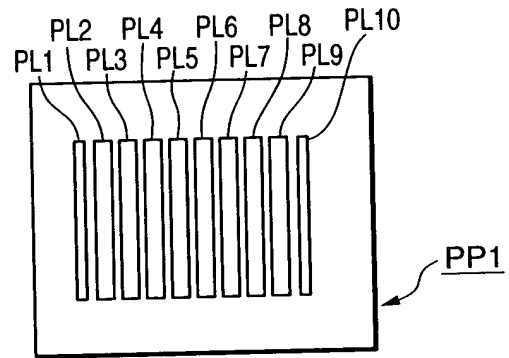


Fig.10(d)

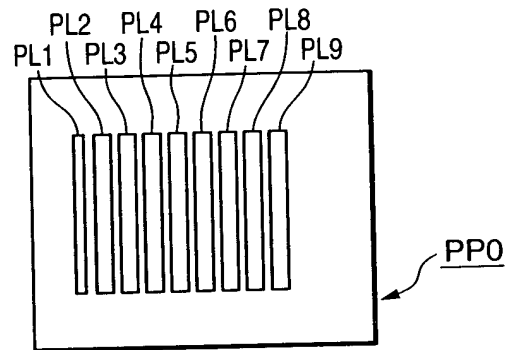


Fig.10(e)

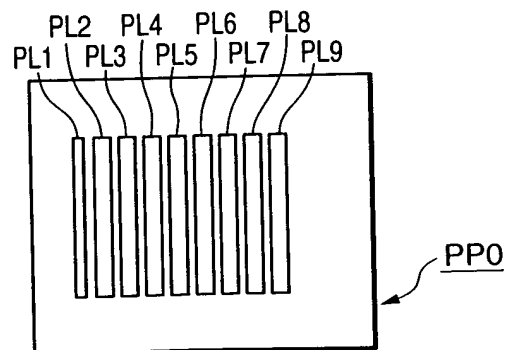


Fig.11

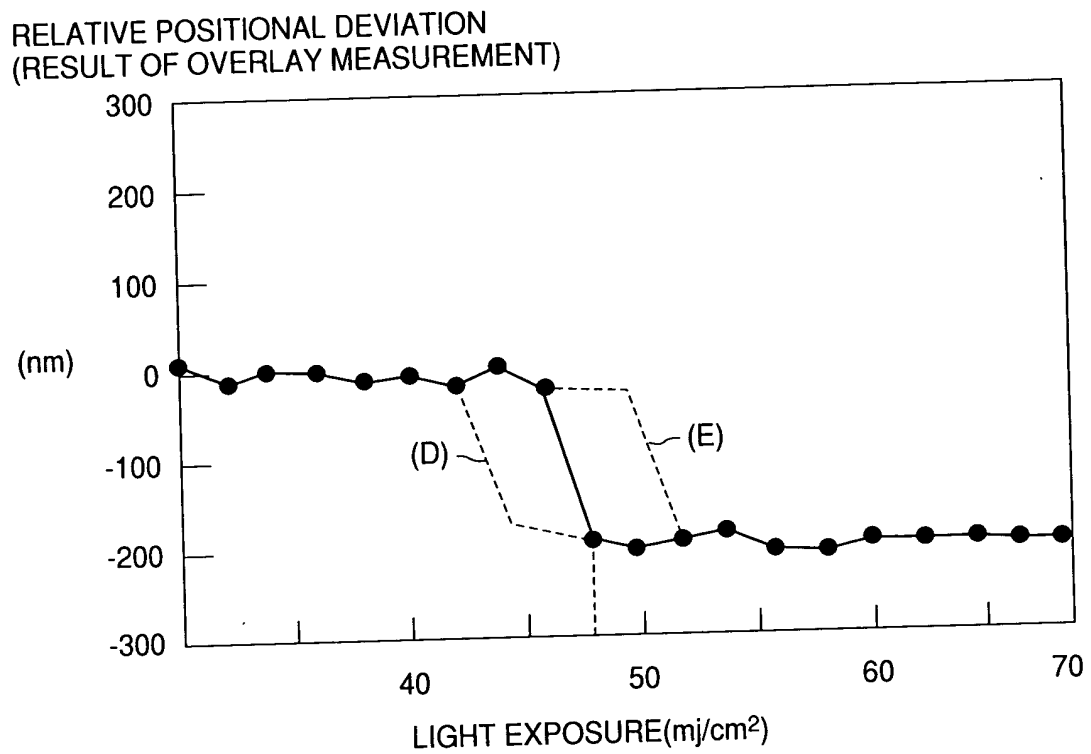


Fig.12

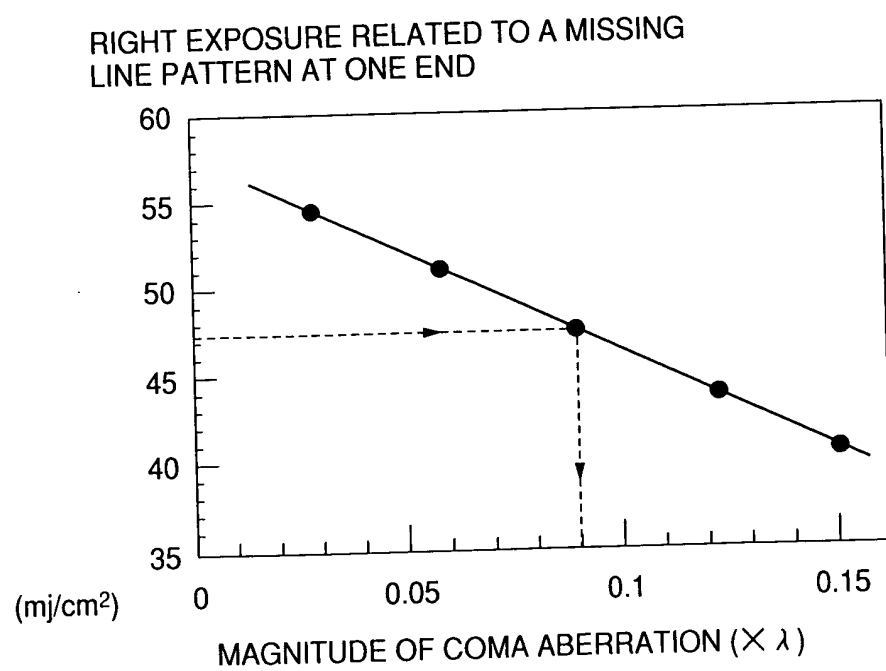


Fig.13(a)

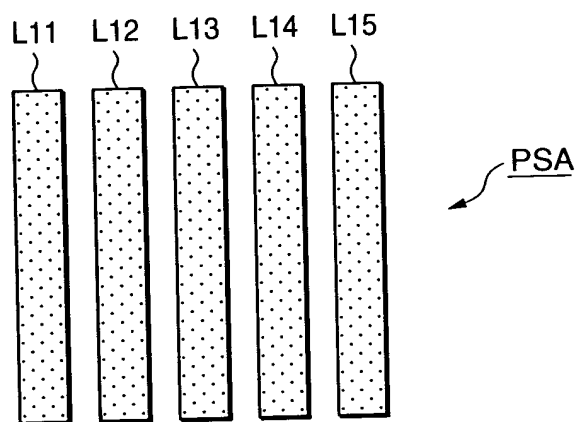


Fig.13(b)

